

ISL9V5036S3S / ISL9V5036P3 / ISL9V5036S3

EcoSPARK® 500mJ, 360V, N-Channel Ignition IGBT

General Description

The ISL9V5036S3S, ISL9V5036P3, and ISL9V5036S3 are the next generation IGBTs that offer outstanding SCIS capability in the D2-Pak (TO-263) and TO-220 plastic package. These devices are intended for use in automotive ignition circuits, specifically as coil drivers. Internal diodes provide voltage clamping without the need for external components.

EcoSPARK® devices can be custom made to specific clamp voltages. Contact your nearest ON Semiconductor sales office for more information.

Formerly Developmental Type 49443

Applications

- · Automotive Ignition Coil Driver Circuits
- · Coil-On Plug Applications

Features

- Industry Standard D²-Pak package
 SCIS Energy = 500mJ at T_J = 25°C
- Logic Level Gate Drive
- · Qualified to AEC Q101
- · RoHS Compliant



Package Symbol COLLECTOR JEDEC TO-262AA JEDEC TO-263AB JEDEC TO-220AB E_CG D2-Pak COLLECTOR COLLECTOR (FLANGE) (FLANGE)

Device Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units V	
BV _{CER}	Collector to Emitter Breakdown Voltage (I _C = 1 mA)	390		
BV _{ECS}	Emitter to Collector Voltage - Reverse Battery Condition (I _C = 10 mA)	24	V	
E _{SCIS25}	At Starting $T_J = 25^{\circ}C$, $I_{SCIS} = 38.5A$, $L = 670 \mu Hy$	500	mJ	
E _{SCIS150}	At Starting $T_J = 150$ °C, $I_{SCIS} = 30$ A, $L = 670 \mu$ Hy	300	mJ	
I _{C25}	Collector Current Continuous, At T _C = 25°C, See Fig 9	46	А	
I _{C110}	Collector Current Continuous, At T _C = 110°C, See Fig 9	31	Α	
V_{GEM}	Gate to Emitter Voltage Continuous	±10	V	
P_{D}	Power Dissipation Total T _C = 25°C	250	W	
	Power Dissipation Derating T _C > 25°C	1.67	W/°C	
TJ	Operating Junction Temperature Range	-40 to 175	°C	
T _{STG}	Storage Junction Temperature Range	-40 to 175	°C	
TL	Max Lead Temp for Soldering (Leads at 1.6mm from Case for 10s)	300	°C	
T _{pkg}	Max Lead Temp for Soldering (Package Body for 10s)	260	°C	
ESD	Electrostatic Discharge Voltage at 100pF, 1500Ω	4	kV	

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Device Marking		Device	Package	Reel Size	•	Tape Wid	dth	Quantity
V5036S		ISL9V5036S3ST	TO-263AB	330mm		24mm		800
V5036P		ISL9V5036P3	TO-220AA	Tube		N/A		50
V5036S		ISL9V5036S3	TO-262AA	Tube		N/A		50
V5036S		ISL9V5036S3S	TO-263AB	Tube		N/A		50
lectric	al Chara	acteristics T _A = 25°C	unless otherwise	noted	<u> </u>		· ·	
Symbol		Parameter	Test Co		Min	Тур	Max	Units
ff State	Characte	ristics						
BV _{CER}	Collector to	o Emitter Breakdown Voltag	$R_G = 1K\Omega$, Se	$I_C = 2\text{mA}, V_{GE} = 0,$ $R_G = 1\text{K}\Omega, \text{ See Fig. 15}$ $T_J = -40 \text{ to } 150^{\circ}\text{C}$		360	390	V
BV _{CES}	Collector to	o Emitter Breakdown Voltag	e $I_C = 10\text{mA}, V_G$ $R_G = 0$, See F	$I_C = 10$ mA, $V_{GE} = 0$, $R_G = 0$, See Fig. 15 $T_{J} = -40$ to 150°C		390	420	V
BV _{ECS}	Emitter to	Collector Breakdown Voltag	e $I_C = -75\text{mA}, V_C$ $T_C = 25^{\circ}\text{C}$	$I_C = -75$ mA, $V_{GE} = 0$ V, $T_C = 25$ °C		-	-	V
BV _{GES}	Gate to Emitter Breakdown Voltage		$I_{GES} = \pm 2mA$	ŭ		±14	-	V
I _{CER}	Collector to Emitter Leakage Current		$V_{CER} = 250V,$	T _C = 25°C	-	-	25	μA
			$R_G = 1K\Omega$, See Fig. 11	T _C = 150°C	-	-	1	mA
I _{ECS}	Emitter to Collector Leakage Current		V _{EC} = 24V, See	e T _C = 25°C	-	-	1	mA
			Fig. 11	$T_C = 150$ °C	-	-	40	mA
R ₁	Series Gate Resistance				-	75	-	Ω
R_2	Gate to Er	nitter Resistance				-	30K	Ω
n State	Characte	ristics						
V _{CE(SAT)}	Collector to	o Emitter Saturation Voltage	$I_C = 10A,$ $V_{GE} = 4.0V$	T _C = 25°C, See Fig. 4	-	1.17	1.60	V
V _{CE(SAT)}	Collector to Emitter Saturation Voltage		$I_C = 15A,$ $V_{GE} = 4.5V$	T _C = 150°C	-	1.50	1.80	V
ynamic	Characte	ristics						
Q _{G(ON)}	Gate Char	ge		I _C = 10A, V _{CE} = 12V, V _{GE} = 5V, See Fig. 14		32	-	nC
V _{GE(TH)}	Gate to Er	nitter Threshold Voltage	$I_C = 1.0 \text{mA},$	$T_C = 25$ °C	1.3	-	2.2	V
			V _{CE} = V _{GE,} See Fig. 10	T _C = 150°C	0.75	-	1.8	V
V_{GEP}	Gate to Er	nitter Plateau Voltage	$I_C = 10A$,	$V_{CE} = 12V$	-	3.0	-	V
	Charact	eristics						
witching			V _{CF} = 14V, R _I	V_{CE} = 14V, R_L = 1 Ω , V_{GE} = 5V, R_G = 1K Ω T_J = 25°C, See Fig. 12		0.7	4	μs
	Current Tu	ırn-On Delay Time-Resistive				2.1	7	шс
witching t _{d(ON)R} t _{rR}	_	rn-On Delay Time-Resistive se Time-Resistive	V _{GE} = 5V, R _G		-	2.1	'	μδ
t _{d(ON)R}	Current Ri		$V_{GE} = 5V, R_G = T_J = 25$ °C, See	e Fig. 12	-	10.8	15	
t _{d(ON)R}	Current Ri	se Time-Resistive	$V_{GE} = 5V$, $R_G = T_J = 25$ °C, See	e Fig. 12 = 2mH, = 1KΩ				µs µs

TO-263, TO-220, TO-262

0.6

°C/W

Thermal Characteristics

Thermal Resistance Junction-Case

 $R_{\theta JC}$

Typical Characteristics

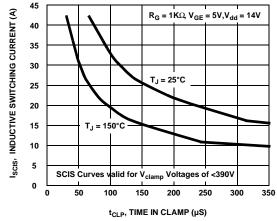


Figure 1. Self Clamped Inductive Switching Current vs Time in Clamp

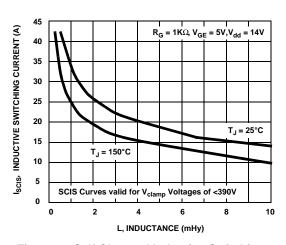


Figure 2. Self Clamped Inductive Switching Current vs Inductance

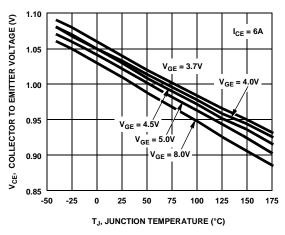


Figure 3. Collector to Emitter On-State Voltage vs Junction Temperature

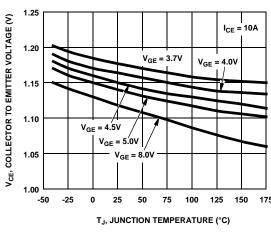


Figure 4.Collector to Emitter On-State Voltage vs Junction Temperature

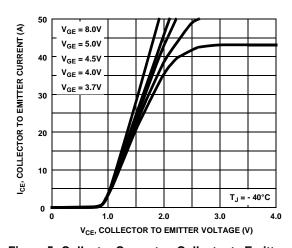


Figure 5. Collector Current vs Collector to Emitter On-State Voltage

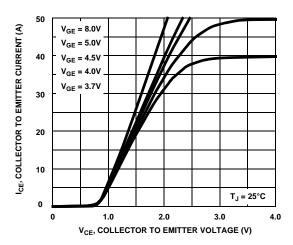


Figure 6. Collector Current vs Collector to Emitter On-State Voltage

Typical Characteristics (Continued) V_{GE} = 8.0V I_{CE}, COLLECTOR TO EMITTER CURRENT (A) V_{GE} = 5.0V $V_{GF} = 4.5V$ $V_{GE} = 4.0V$ $V_{GE} = 3.7V$ 30 20 10 $T_J = 175^{\circ}C$ V_{CE}, COLLECTOR TO EMITTER VOLTAGE (V) Figure 7. Collector to Emitter On-State Voltage vs **Collector Current** 50 V_{GE} = 4.0V 40

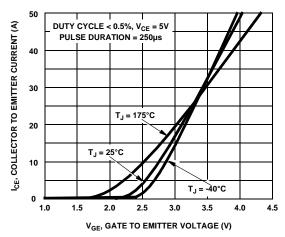
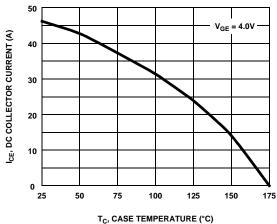


Figure 8. Transfer Characteristics



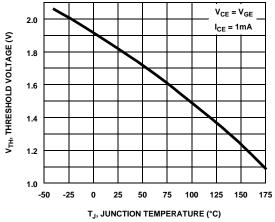
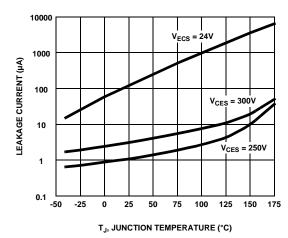


Figure 9. DC Collector Current vs Case **Temperature**

Figure 10. Threshold Voltage vs Junction **Temperature**



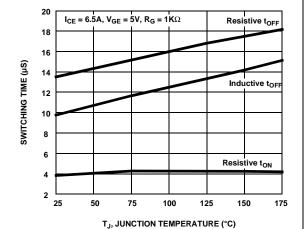
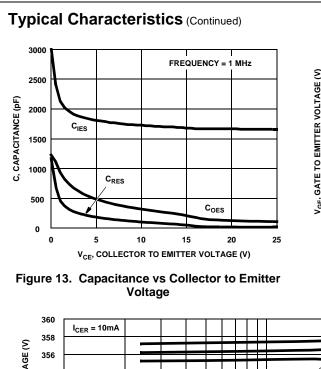


Figure 11. Leakage Current vs Junction **Temperature**

Figure 12. Switching Time vs Junction Temperature



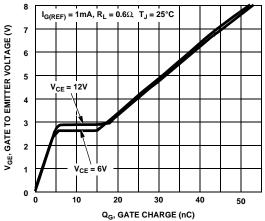


Figure 14. Gate Charge

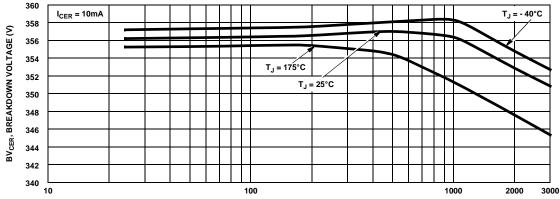


Figure 15. Breakdown Voltage vs Series Gate Resistance

 R_G , SERIES GATE RESISTANCE ($k\Omega$)

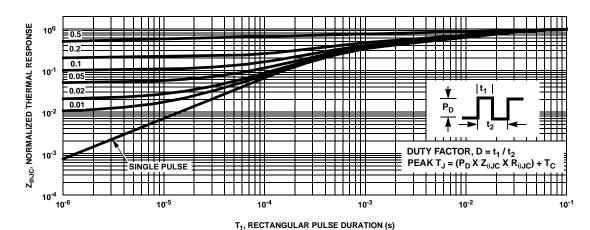
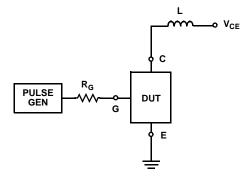


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

Test Circuits and Waveforms



 $R_{G} = 1K\Omega$ G DUT = V_{CE}

Figure 17. Inductive Switching Test Circuit

Figure 18. t_{ON} and t_{OFF} Switching Test Circuit

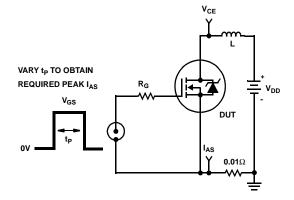


Figure 19. Energy Test Circuit

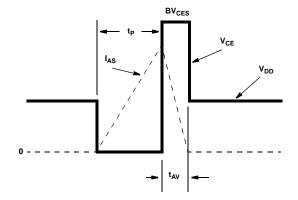
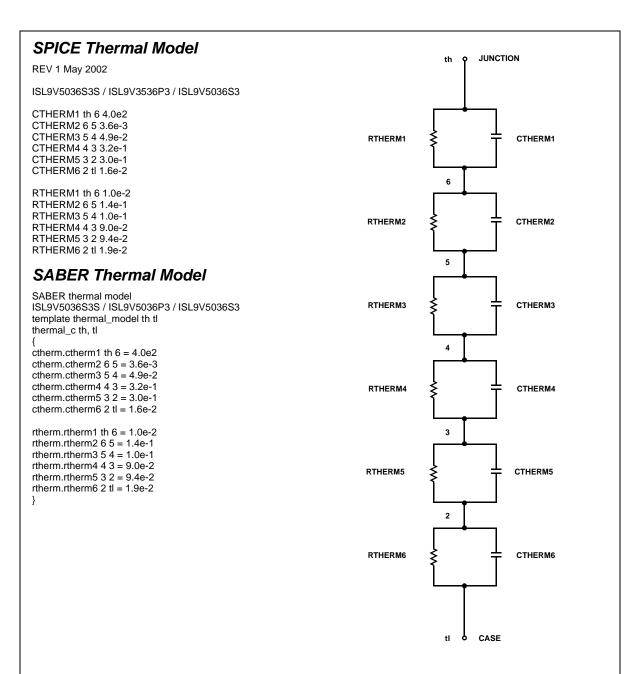


Figure 20. Energy Waveforms



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